"Advanced Fiducial Alignment for Photolithographic Probe Cards"

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Introduction

- Fiducial alignment objective
- Drivers for Fiducial alignment
- Why Fiducial alignment?
- Advantages of photolithographic probe cards for Fiducial alignment





Fiducial Based Alignment Objective

- Develop a new method for accurately aligning the probe card to the device pads for tight pitch applications.
- Increase the overall test cell reliability, capability and productivity for production applications. (OEE)
- Develop a method of communicating detailed probe card information based on a simple file format.





Drivers for Fiducial alignment?

- Device technology shrinking to the sub 0.13 µm technology level and specialized devices require small bond pad technology - 30 um pad sizes.
- Consumer applications also require small pads and tight pitches - 40 um pitches.
- Advancing probe card technology with tight pin pitch require advance probe to pad alignment process
- Probe to pad alignment on small pad devices





Why Fiducial Alignment?

- Provides high accuracy reference points.
- Offers a fast file download method to the prober for each probe tip location to increase productivity.
- Decreases the time needed for the prober to accurately locate the probe card pins.
- Extremely accurate and fast solution!





Photolithographic Probe Card Advantages for Fiducial Alignment

- Photolithography offers 0.5 µm accuracy resolution enabling solutions for probing small pads and fine pitch applications.
- Fiducials have the same high accuracy as that of the mask.
- Extremely low card to card variation in pin position due to photolithography.
- Photolithographic based Fiducials do not change location or accuracy over time or with wear.
- No additional cost to implement Fiducials in the design.





Fiducial Alignment Program

Probe Card

- Develop a photolithography based probe card
- Develop a fiducial design for pin location
- Develop a fiducial structure
- Build a photolithographic probe card with Fiducials

Wafer Prober

- Develop the prober software to recognize and find Fiducials
- Use Fiducials to calculate pin locations
- Develop a standard file format for downloading probe card information
- Test Automatic Probe To Pad Alignment (APTPA) using <u>Fid</u>ucial alignment



Design and Fabrication of Photolithography Probe Cards with Fiducials





Fiducial Theory – Image Identification

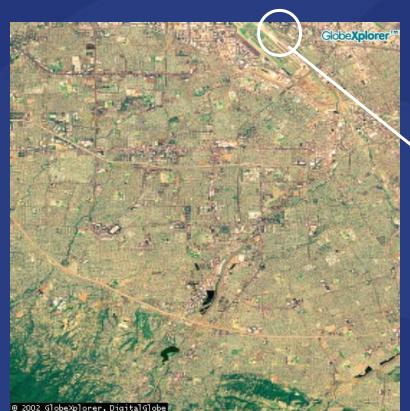


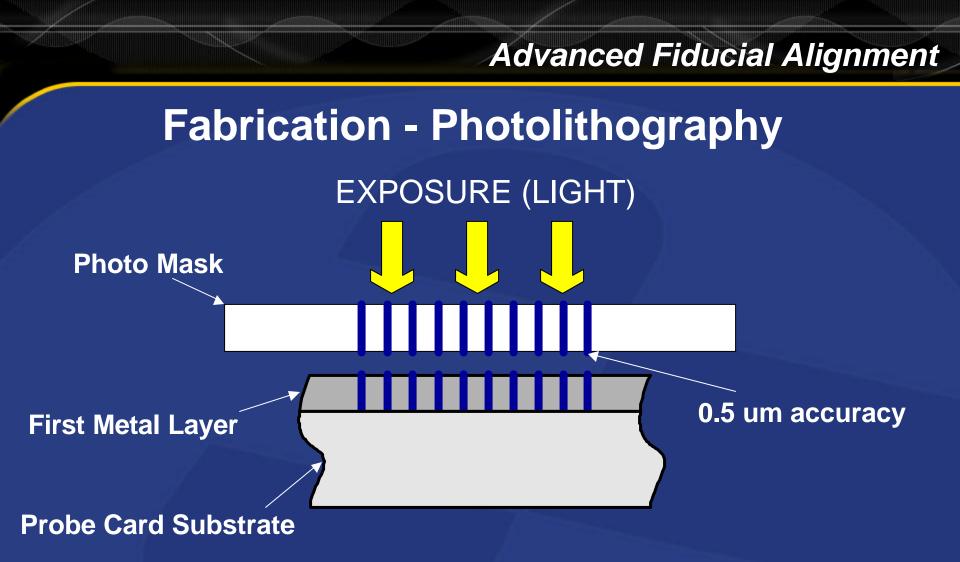
Image from: www.mapquest.com With a known image, you can find a location based upon "geography"

Or you can find a given shape/feature then relate it to the desired location.





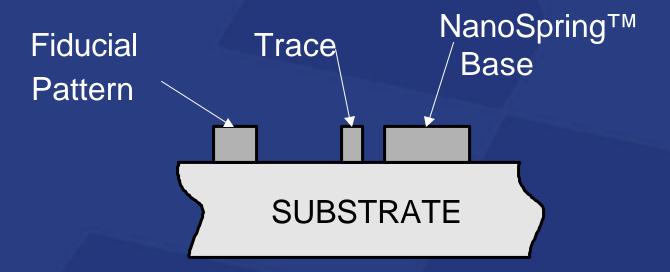








Fabrication - Etch



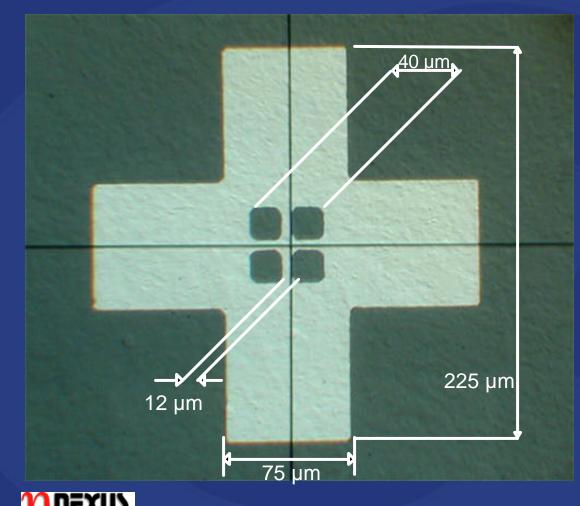
Fiducial formed with the same accuracy as the probe base.
Fiducial kept clear of passivation for additional accuracy.



NanoSpring is a trademark of NanoNexus
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Fiducial Target Specifications



- Four targets total
- Large structure for low magnification
- Small structure (center) for high magnification



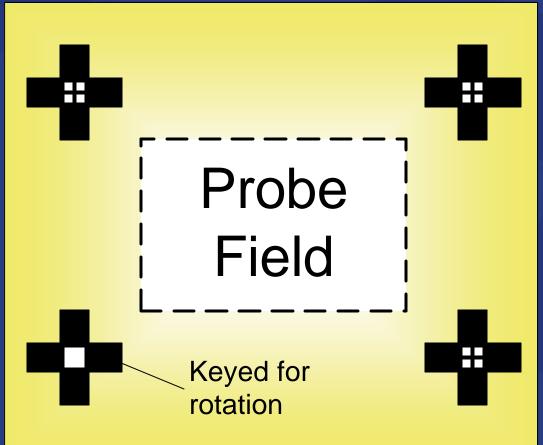
Rotation Fiducial Design

 One Fiducial with blank center to indicate rotation.





Layout of the Fiducials on the Probe Card



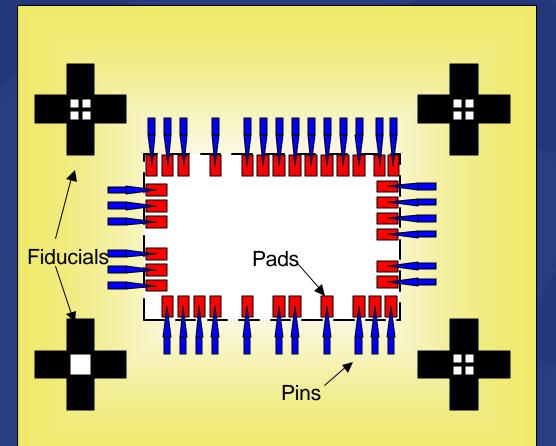
 Targets are outside the area of the probe "field".

- Ideal location on the diagonals.
- One fiducial keyed to indicate rotation.
- Spacing can provide identification.





Probe Field Construction



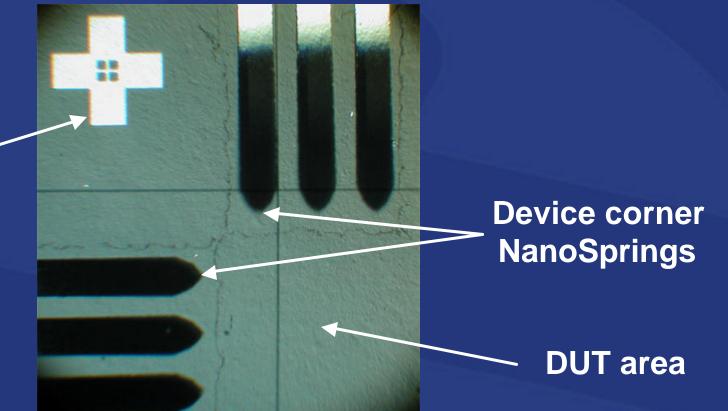
- Pins located within probe field as required by application.
- Probe field need only contain probe / pin tips (not entire structure).
- Need only data of X-Y location of pins with respect to fiducials.





Actual Fiducial of NanoSpring Probe Card

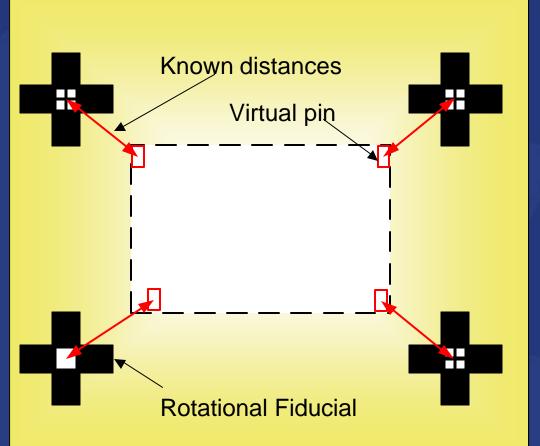
Fiducial outside of pin area







Known Distances



- By knowing the Fiducial locations it is possible to determine the virtual pin locations using downloaded data.
- Centroid of the probe card can be calculated directly from the Fiducial locations or from the nominal corner pin locations (current method)





Requirements for Fiducial Alignment on Wafer Prober Systems





Considerations of Probe Card Support on Probers

Significant variations in tip appearance for prober vision systems
 Probers provides only card specific solutions

Add a new probe card support to a prober is very time consuming

Communication between probe card and prober manufacturers
 Probers have no knowledge on what to expect
 Long probe card support cycle

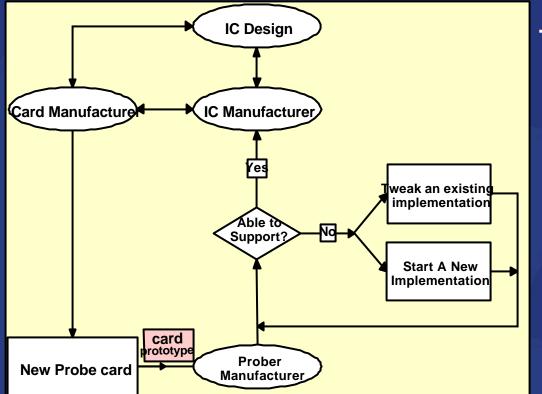
No portability of support between probers from different vendors

Difficult to track physical properties of individual probe card.





Typical Process Flow for Probe Card Delivery



Trial and error approach: time consuming and complicated

- No prior knowledge of the probe card appearance
- Card support is very complicated due to the appearances of the tips of different probe cards
- Only communication is at the time of probe card prototyping
- Not sure if the prototype will be the same as the final product





Fiducial Alignment as the Solution

• Fiducials:

- Less variation under different optics/cameras
- No wear and tear in the testing process

Potential for standardization of PC description file:

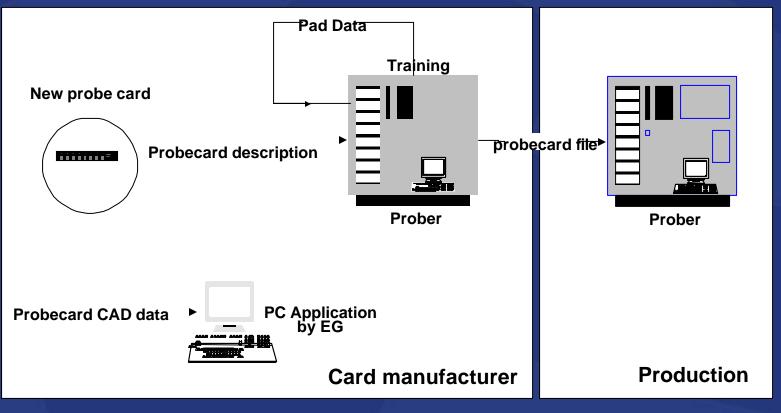
- Provide an effective way of communication between probe card and prober manufacturers
- Probers know what to expect of a probe card
- Provide portability of probe card support between different probers
- All probe card data in one place for easy tracking of probe cards
- Can archive data to be used on other probers

Potential to use any identifiable image as Fiducials





With Fiducials Probe Card Delivery Process is Simplified







With Fiducials Probe Card Delivery Process is Simplified

Probe card and prober manufacturer support is simplified

- Probe card manufacturer provides a detailed description of the probe card through a file
- Prober manufacturer works on a solution in the card design stage.

Simplified test floor production activity

- Most of the data is generated off-line with less interruption of production
- The file is portable between probers.
- Minimum amount of training is needed on individual probers

Easy to add future enhancements

- Large amount of data may be embedded in the file
- Easy probe card tracking

IEXUS



Probe Card Description File Requirements

File Structure

- Mandatory sections for probe card auto align process
- Optional sections for functional enhancements

File Format

- Editable and readable by plain text editors
- Plain text for mandatory sections
- Plain text or Base64 encoded data for optional sections
- Optional sections may be encrypted by the provider

File Error checking

MD5 or SHA256 based data integrity checking







Content of the Probe Card Description File

Mandatory file sections

- File version and probe card ID section
- Global Probe Card Data units, reference frame....
- Fiducial Section: reference and validation fiducials
- Die Section how many, layout....
- Tip Section where, name, how many....
- Data integrity checking sections

Optional file sections

- Card usage information may be machine and time stamped
- Card manufacturer data section private data
- Metrology data section measurements
- Prober data section Private data to support probe card align
- Other data sections extension data





Design Goal: Probe Card Description File

- Simplicity
 - Support the necessary probe card information only
- Portability
 - Mandatory section provide sufficient data to support auto align
 - Different probers may have their own private data sections to support portability.
- File Tracing
 - Each file may be associated with the serial number of the card
- Flexibility
 - Customer may add their own private data sections for various purposes
 - A data field may present or absent for different cards





Probe Card Description File: An Example

PRDFVersion: 0.01 ProbeCardName: nanonexus-Test1 ProbeCardIDType: Manual ProbeCardID: testprbcard SerialNumber: 01234567 ReservedField: DateCreated: 03/07/2002 DateLastModified: 03/07/2002 IntegrityChecking: MD5 Manufacturer: NanoNexus: CoordinateSystem: BottomView Units: mirons CenterLocation: 0.000000 0.000000 Angle: 0.000000 RecomendedOverDrive: 4.000000 3:000 5:000 RecomendedCleanMethod: Scrub RecomendedCleanInterval: 3000 2000 5000 ProbecardIDLocation: none Probecard/DFijeldSize: 0.0 ProbecardIDFijeldParameter: 0 FiducialLighting: Coaxial: 200 200 0 NumberofReferenceFiducials: 4 ReferenceFiducialName: first-low-resolution-reference ReferenceFiducialResolution: COARSE ReferenceFiducialLocation: 3389:17 2599:3:152.000000 ReferenceFiducialPatternType: 1 ReferenceFiducialParameters: 290.000000 290.000000 3: 4 ReferenceFiducialName: first-high-resolution-reference ReferenceFiducialResolution: FINE ReferenceFiducialLocation: 3389,170000 2599,300000 152,000000 ReferenceFiducialPatternType: 1 ReferenceFiducialParameters: 80.000000 80.000000 3: 4 ReferenceFiducialName: second-low-resolution-reference ReferenceFiducialResolution: COARSE ReferenceFiducialLocation: -3352.6500 -2599.300000 152:000000 ReferenceFiducialPatternType: 0 ReferenceFiducialParameters: 290.000000 290.000000 9: 10: ReferenceFiducialName: second-high-resolution-reference ReferenceFiducialResolution: FINE ReferenceFiducialLocation: -3352.6500 -2599.300000 152:000000 ReferenceFiducialPatternType: 0 ReferenceFiducialParameters: 80.000000 80.000000 9 10 NumberofValidationFiducials: 2 ValidationFiducialName: validation ValidationFiducialResolution: COARSE ValidationFiducialLocation: -3352.650000 2599.350000 0.000000 ValidationFiducialPatternType: 2 ValidationFiducialParameters: 290.000000 290.000000 5 6: ValidationFiducialName: validation-fine ValidationFiducialResolution: FINE ValidationFiducialLocation: -3352.650000 2599.350000 0.000000 ValidationFiducialPatternType: 2 ValidationFiducialParameters: 80.000000 80.000000 5 6: MaxValidationErrorBound: -200:0: 200:0: -200:0: 200:0 NumberofDiesOnCard: 1 DieOrientation: 0 DiesInaRow: 1 DieMatrix: NumberofTips: 48 TipLighting: Oblique; 200 200 0 TipType: 1 TipParameters: 4.000000 5.000000 6.000000 FirstTipLocation: 2939.000000 2149.000000 TipSteps: 2 TipRange: 0 22 4 2939:000000 2149:000000 186:0 TipRange: 23: 47/3: -2903.00000) -2149.00000 186:0) MD5HashValue:





Set Up of Fiducial Probe Card

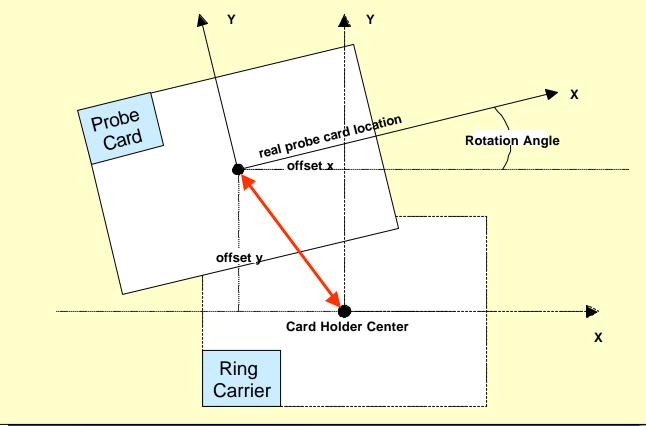
- Obtain or build the probe card description file
 - File normally provided by the card manufacturer
 - Or a text file description can be built
- Load the probe card description file on the prober
- Select appropriate probe card file from the prober
 - Through EGComander UI as any other probe cards
- Train the Fiducials if required
 - You will be prompt to start training if the fiducial are not trained yet.
 - A Probe card manufacturer may have done this already. In this case you may directly run auto align using the Fiducials
- Auto align using the Fiducials at any time





Fiducial Align Offset and Rotation Calculation

Determine probe card rotation angle a and offset (x,y)





Fiducial Align Error Analysis

Fiducial Location Error

$$d_r = d_{motion} + d_{training} + d_{pattern-search} + d_{fiducial} = d_{systematic} + d_{random}$$

Angular error use the fiducials (assume Gussian error)

$$\boldsymbol{d}_{a} \approx \boldsymbol{d}_{a-systematic} + \frac{\sqrt{2} \boldsymbol{d}_{a-systematic}}{(N-1)} \sqrt{\sum_{\boldsymbol{R}_{k,l}^{2}}^{1}}$$

Offset error use all fiducials

$$\Delta_{r} = \boldsymbol{d}_{systematic} + \frac{1}{\sqrt{N}} \boldsymbol{d}_{r-random}$$





Fiducial Align Error Analysis

Assume systematic error is small (Prober is calibrated and the fiducials are produced and trained accurately) we have:



 $\Delta_{r} = \frac{1}{\sqrt{N}} d_{r^{-random}}$

 $d_{a} \approx \frac{\sqrt{2}d_{r-random}}{\sqrt{N-1}\cdot R}$ Where *R* is the average distance between the fiducials

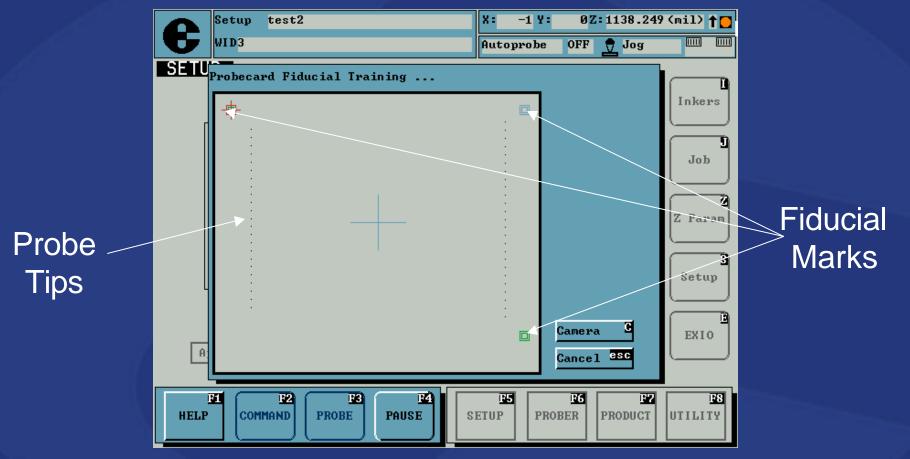
The greater number of fiducials, the better the accuracy





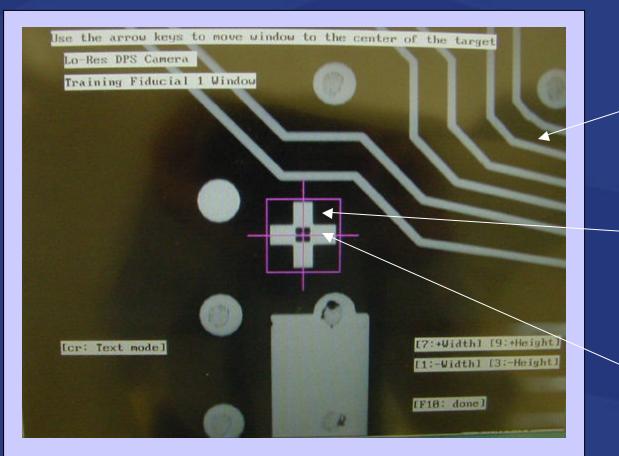
electrog

Actual Fiducial Screen Electroglas 4090µ Prober





Actual Fiducial Mark on EG4090µ prober



Lithography Probe Card

Fiducial Mark

Prober Vision Target





Fiducial Alignment Conclusions

Elegant solution:

- Solves challenges of fine pitch and small pad probing
- Enables high accuracy probe card technology
- Automates prober setup:
 - Easy pin identification and location
 - Greater operational flexibility
- Increases performance of test cell

Results:

- Concept demonstrated
- Open industry standard proposed



